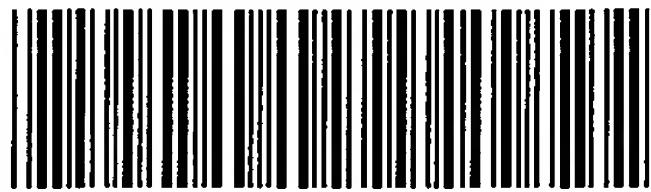


Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/668,197	HSIEH, YOU-JUN	
Examiner	Art Unit	
Dennis-Doon Chow	2677	

SEARCHED			
Class	Subclass	Date	Examiner
345	156	3/15/2006	CHOW
	168-172		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR